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Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 128675		APPLICATION NO. 10/589,962	
INFORMATION DISCLOSURE STATEMENT							
(Use several sheets if necessary)							
				APPLICANT(S) Hiroyuki NAGASAKA			
				FILING DATE August 18, 2006		GROUP 1752	
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
/C.R./	1	5,534,970	07/09/1996	NAKASHIMA ET AL.			
	2	5,448,332	09/05/1995	SAKAKIBARA ET AL.			
	3	4,780,617	10/25/1988	UMATATE ET AL.			
	4	6,262,796 B1	07/17/2001	LOOPSTRA ET AL.			
	5	5,825,043	10/20/1988	SUWA			
	6	4,346,164	08/24/1982	TABARELLI ET AL.			
	7	4,480,910	11/06/1984	TAKANASHI ET AL.			
	8	5,610,683	03/11/1997	TAKAHASHI ET AL.			
	9	5,715,039	02/03/1998	FUKUDA ET AL.			
	10	2004/0165159 A1	08/26/2004	LOF ET AL.			
	11	2003/0025890 A1	02/06/2003	NISHINAGA			
/C.R./	12	6,897,963 B1	05/24/2005	TANIGUCHI ET AL.			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
/C.R./	13	JP A 10-340846	12/22/1998	JAPAN	X	X	
/C.R./	14	JP A 2000-21763	01/21/2000	JAPAN	X	X	
	15	JP A 2000-38430	02/23/2000	JAPAN	X	X	
	16	JP A 2001-313250	11/09/2001	JAPAN	X	X	
	17	JP A 86-349981	12/22/1994	JAPAN	X	X	
	18	JP A 86-203403	10/07/1994	JAPAN	X	X	
	19	JP A 61-044430	03/04/1986	JAPAN	X	X	
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
EXAMINER /Christina Riddle/				DATE CONSIDERED 01/27/2009			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: November 30, 2006

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Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 128675		APPLICATION NO. 10/589,962	
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Examiner Initials	Cite No.	Document Number	Date	Name			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
	20	JP A 2000-311704	09/05/2000	JAPAN	X	X	
	21	JP A 2000-104304	08/10/2000	JAPAN	X	X	
	22	JP A 06-124873	05/06/1994	JAPAN	X	X	
	23	JP A 10-383114	11/13/1998	JAPAN	X	X	
	24	JP A 10-134039	08/09/1998	JAPAN	X	X	
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	28	JP A 58-202448	11/23/1983	JAPAN	X	X	
	29	JP A 63-65326	03/24/1988	JAPAN		X	
	30	JP A 63-157410	06/00/1988	JAPAN		X	
	31	JP A 04-305915	10/28/1992	JAPAN	X	X	
	32	JP A 04-305917	10/28/1992	JAPAN	X	X	
	33	JP A 06-63872	03/22/1993	JAPAN	X	X	
	34	JP A 06-124873	05/06/1994	JAPAN	X	X	
	35	JP A 07-330000	08/18/1995	JAPAN	X	X	
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
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